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TABLE OF CONTENTS

SESSION 1

SESSION 1A: MICROPROCESSOR TEST

Efficient Array Characterization in the UltraSPARC T2	1
<i>Thomas Ziaja, P.J. Tan</i>	
Instruction-Level Impact Comparison of RT- vs. Gate-Level Faults in a Modern Microprocessor Controller	7
<i>Michail Maniatakos, Naghmeh Karimi, Chandra Tirumurti, Abhijit Jas, Yiorgos Makris</i>	
Modeling and Testing Comparison Faults of TCAMs with Asymmetric Cells	13
<i>Yong-Jyun Hu, Yu-Jen Huang, Jin-Fu Li</i>	

SESSION 1B: FAULT MODELS

An Electrical Model for the Fault Simulation of Small Delay Faults Caused by Crosstalk Aggravated Resistive Short Defects	19
<i>N. Houarche, M. Comte, M. Renovell, A. Czutro, P. Engelke, I. Polian, B. Becker</i>	
Small Delay Fault Model for Intra-Gate Resistive Open Defects	25
<i>Masayuki Arai, Akifumi Suto, Kazuhiko Iwasaki, Katsuyuki Nakano, Michihiro Shintani, Kazumi Hatayama, Takashi Aikyo</i>	
Defect Detection Differences between Launch-Off-Shift and Launch-Off-Capture in Sense-Amplifier-Based Flip-Flop Testing	31
<i>Haluk Konuk</i>	

SESSION 2

SESSION 2A: ROBUST DESIGN AND FAULT TOLERANCE

Soft-Error Hardening Designs of Nanoscale CMOS Latches	37
<i>Sheng Lin, Yong-Bin Kim, Fabrizio Lombardi</i>	
Exploiting Unused Spare Columns to Improve Memory ECC	43
<i>Rudrajit Datta, Nur A. Toubia</i>	
An Adaptive-Rate Error Correction Scheme for NAND Flash Memory	49
<i>Te-Hsuan Chen, Yu-Ying Hsiao, Yu-Tsao Hsing, Cheng-Wen Wu</i>	

SESSION 2B: DELAY FAULT TESTING I

Compact Delay Test Generation with a Realistic Low Cost Fault Coverage Metric	55
<i>Zheng Wang, Duncan M.H. Walker</i>	
Recursive Path Selection for Delay Fault Testing	61
<i>Jaeyong Chung, Jacob A. Abraham</i>	

A Synthesis Method to Alleviate Over-Testing of Delay Faults Based on RTL Don't Care Path Identification	67
<i>Yuki Yoshikawa, Satoshi Ohtake, Tomoo Inoue, Hideo Fujiwara</i>	

SESSION 3

SESSION 3A: DEBUG

Automated Selection of Signals to Observe for Efficient Silicon Debug	73
<i>Joon-Sung Yang, Nur A. Toubia</i>	
A New Post-Silicon Debug Approach Based on Suspect Window	79
<i>Jianliang Gao, Yinhe Han, Xiaowei Li</i>	
Automated Debug of Speed Path Failures Using Functional Tests	85
<i>Richard McLaughlin, Srikanth Venkataraman, Carlston Lim</i>	

SESSION 3B: DELAY FAULT TESTING II

Output Hazard-Free Transition Delay Fault Test Generation	91
<i>Sreekumar Menon, Adit D. Singh, Vishwani Agrawal</i>	
Efficient Scheduling of Path Delay Tests for Latch-Based Circuits	97
<i>Kun Young Chung, Sandeep K. Gupta</i>	
Effective and Efficient Test Pattern Generation for Small Delay Defect	105
<i>Sandeep Kumar Goel, Narendra Devta-Prasanna, Ritesh P. Turakhia</i>	

SESSION 4

Special Session 4A: Panel: Apprentice - VTS Edition: Season 2	111
<i>Kee Sup Kim</i>	
Special Session 4B: Panel: DFT and Test Problems from the Trenches	112
<i>Haluk Konuk</i>	

SESSION 5

SESSION 5A: DIAGNOSIS

Multiple-Fault Diagnosis Using Faulty-Region Identification	113
<i>Megn-Jai Tasi, Mango C.T. Chao, Jing-Yang Jou, Meng-Chen Wu</i>	
Predictive Test Technique for Diagnosis of RF CMOS Receivers	119
<i>K. Suenaga, S. Bota, R. Picos, E. Isern, M. Roca, E Garcia-Moreno</i>	
Controlling DPPM through Volume Diagnosis	124
<i>Xiaochun Yu, Yen-Tzu Lin, Wing-Chiu Tam, Osei Poku, R.D. Blanton</i>	

SESSION 5B: DELAY FAULT TESTING AND SIGNAL INTEGRITY

Scalable Compact Test Pattern Generation for Path Delay Faults Based on Functions	130
<i>Edward Flanigan, Spyros Tragoudas, Arkan Abdulrahman</i>	

The ATPG Conflict-Driven Scheme for High Transition Fault Coverage and Low Test Cost	136
<i>Zhen Chen, Dong Xiang, Boxue Yin</i>	

A High-Level Signal Integrity Fault Model and Test Methodology for Long On-Chip Interconnections	142
<i>Sunghoon Chun, Yongjoon Kim, Taejin Kim, Sungho Kang</i>	

SESSION 6

SESSION 6A: YIELD

False Path Aware Timing Yield Estimation under Variability	148
<i>Lin Xie, Azadeh Davoodi, Kewal K. Saluja, Abhishek Sinkar</i>	
Bridging DFM Analysis and Volume Diagnostics for Yield Learning - A Case Study	154
<i>Ritesh Turakhia, Mark Ward, Sandeep Kuma Goel, Brady Benware</i>	
Yield and Cost Analysis of a Reliable NoC	160
<i>Saeed Shamshiri, Kwang-Ting Cheng</i>	

SESSION 6B: BIST

Restrict Encoding for Mixed-Mode BIST	166
<i>Abdul-Wahid Hakmi, Stefan Holst, Hans-Joachim Wunderlich, Jürgen Schlöffel, Friedrich Hapke, Andreas Glowatz</i>	
A Scalable, Digital BIST Circuit for Measurement and Compensation of Static Phase Offset	172
<i>Keith A. Jenkins, Lionel Li</i>	
Experimental Validation of a BIST Technique for CMOS Active Pixel Sensors	176
<i>Livier Lizarraga, Salvador Mir, Gilles Sicard</i>	

SESSION 7

SESSION 7A: TEST AND VERIFICATION

Physically-Aware N-Detect Test Relaxation	182
<i>Yen-Tzu Lin, Chukwuemeka U. Ezekwe, R. D. Blanton</i>	
Automatic Selection of Internal Observation Signals for Design Verification	188
<i>Tao Lv, Hua-wei Li, Xiao-wei Li</i>	
STDF Memory Fail Datalog Standard	194
<i>Ajay Khoche, Jay Katz, Sauro Landini, Kochen Liao, Neetu Agrawal, Glenn Plowman, Song-lin Zuo, Liyang Lai, John Rowe, Thomas Zanon</i>	

SESSION 7B: TRANSISTOR AGING AND POWER SUPPLY NOISE

Testing for Transistor Aging	200
<i>Altug Hakan Baba, Subhasish Mitra</i>	

Layout-Aware Pattern Generation for Maximizing Supply Noise Effects on Critical Paths	206
<i>Junxia Ma, Jeremy Lee, Mohammad Tehranipoor</i>	
Understanding Power Supply Droop during At-Speed Scan Testing	212
<i>Pankaj Pant, Joshua Zelman</i>	
Special Session 7C: TTTC 2009 Best Doctoral Thesis Contest	218
<i>Yiorgos Makris, Haralampos Stratigopoulos</i>	

SESSION 8

Special Session 8: New Topics: At-Speed Testing in the Face of Process Variations	219
<i>Bernard Courtois, Chandu Visweswariah</i>	

SESSION 9

Special Session 9: New Topics: Microscale and Nanoscale Thermal Characterization of Integrated Circuit Chips	220
<i>Bernard Courtois, Ali Shakouri</i>	

SESSION 10

SESSION 10A: TEST COMPACTION

Highly X-Tolerant Selective Compaction of Test Responses	221
<i>Grzegorz Mrugalski, Nilanjan Mukherjee, Janusz Rajska, Dariusz Czysz, Jerzy Tyszer</i>	
Dynamic Test Compaction for Transition Faults in Broadside Scan Testing Based on an Influence Cone Measure	227
<i>Dong Xiang, Boxue Yin, Kwang-Ting Cheng</i>	
Maintaining Accuracy of Test Compaction through Adaptive Re-learning	233
<i>Sounil Biswas, R. D. Blanton</i>	

SESSION 10B: TEST AND RADIATION TEST

RT-Level Deviation-Based Grading of Functional Test Sequences	240
<i>Hongxia Fang, Krishnendu Chakrabarty, Abhijit Jas, Srinivas Patil, Chandra Tirumurti</i>	
Analytical Model for Multi-site Efficiency with Parallel to Serial Test Times, Yield and Clustering	246
<i>Naveen Velamati, Robert Daasch</i>	
DfT Reuse for Low-Cost Radiation Testing of SoCs: A Case Study	252
<i>D. Appello, P. Bernardi, S. Gerardin, M. Grosso, A. Paccagnella, P. Rech, M. Sonza Reorda</i>	

SESSION 11

SESSION 11A: ANALOG TEST AND CALIBRATION

On-Line Calibration and Power Optimization of RF Systems Using a Built-In Detector	258
<i>Chaoming Zhang, Ranjit Gharpurey, Jacob A. Abraham</i>	
Calibration and Testing Time Reduction Techniques for a Digitally-Calibrated Pipelined ADC	264
<i>Hsiu-Ming Chang, Chin-Hsuan Chen, Kuan-Yu Lin, Kwang-Ting Cheng</i>	
A Time Domain Method to Measure Oscillator Phase Noise	270
<i>Kenneth Blakkan, Mani Soma</i>	
A Packet Based 2x-Site Test Solution for GSM Transceivers with Limited Tester Resources	276
<i>Erdem Serkan Erdogan, Sule Ozev</i>	

SESSION 11B: EMERGENT TECHNOLOGY AND SECURITY

Design-for-Testability for Digital Microfluidic Biochips	282
<i>Tao Xu, Krishnendu Chakrabarty</i>	
Stuck-Open Fault Leakage and Testing in Nanometer Technologies.....	288
<i>Julio Vazquez, Victor Champac, Chuck Hawkins, Jaume Segura</i>	
SS-KTC: A High-Testability Low-Overhead Scan Architecture with Multi-level Security Integration	294
<i>Unni Chandran, Dan Zhao</i>	
Characterization of Effective Laser Spots during Attacks in the Configuration of a Virtex-II FPGA.....	300
<i>Gaetan Canivet, Regis Leveugle, Jessy Clediere, Frederic Valette, Marc Renaudin</i>	
Special Session 11C: Embedded Tutorial: System-on-a-Chip Power Management Implications on Validation and Testing	306
<i>Bhanu Kapoor</i>	

SESSION 12

Special Session 12A: Panel: Analog Characterization and Test: The Long Road to Realization	307
<i>Arani Sinha, Amitava Majumdar, Vasu Ganti</i>	
Special Session 12B: Panel: Functional Verification Planning and Management - Are Good Intentions Good Enough?	308
<i>Andrew Piziali</i>	

Author Index